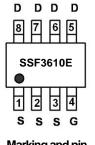
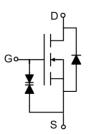


### **Main Product Characteristics:**

$V_{DSS}$	25 V
R <sub>DS</sub> (on)	6.8 mΩ(typ.)
I <sub>D</sub>	18A







SOP-8

Marking and pin Assignment

Schematic diagram

### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



## **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

## **Absolute max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V①	18	۸
I <sub>DM</sub>	Pulsed Drain Current②	72	А
P <sub>D</sub> @TC = 25°C	Power Dissipation③	3.1	W
V <sub>DS</sub>	Drain-Source Voltage	25	V
V <sub>GS</sub>	Gate-to-Source Voltage	± 12	V
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C

#### **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
$R_{\theta JA}$	Junction-to-ambient (t ≤ 10s) ④	ı	40	°C/W





# **Electrical Characterizes** $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	25	_	_	V	V <sub>GS</sub> = 0V, ID = 250μA
		_	6.8	10		V <sub>GS</sub> =10V, I <sub>D</sub> =5A
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	_	7.6	12	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =6A
		_	10.4	14		V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A
V <sub>GS(th)</sub>	Gate threshold voltage	1	1.3	2.5	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	$V_{DS} = 25V, V_{GS} = 0V$
1	Gate-to-Source forward leakage	_	_	10		V <sub>GS</sub> = 10V
$I_{GSS}$	Gate-to-Source forward leakage	_	_	-10	μA	V <sub>GS</sub> = -10V
Qg	Total gate charge	_	15.4	_		$I_D = 4A$ ,
$Q_{gs}$	Gate-to-Source charge	_	3.6	_	nC	V <sub>DS</sub> =10V,
$Q_{gd}$	Gate-to-Drain("Miller") charge	_	5.8	_		V <sub>GS</sub> = 4.5V
t <sub>d(on)</sub>	Turn-on delay time	_	6.6	_		V 40V VDC 40V
t <sub>r</sub>	Rise time	_	4.6	_		V <sub>GS</sub> =10V, VDS=10V,
t <sub>d(off)</sub>	Turn-Off delay time	_	33.0	_	ns	$R_L=10\Omega$ ,
t <sub>f</sub>	Fall time	_	20.3	_		$R_{GEN}=3\Omega$
C <sub>iss</sub>	Input capacitance	_	1260	_		$V_{GS} = 0V$
C <sub>oss</sub>	Output capacitance	_	353	_	pF	V <sub>DS</sub> = 10V
C <sub>rss</sub>	Reverse transfer capacitance		295	_		f = 1MHz

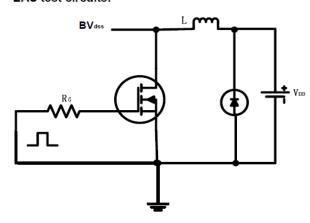
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
la	Continuous Source Current			18	А	MOSFET symbol
Is	(Body Diode)	_		10	A	showing the
1	Pulsed Source Current			72	А	integral reverse
I <sub>SM</sub>	(Body Diode)	_	_	12	A	p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	0.75	0.9	V	I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	10.5	_	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> =15A,
Q <sub>rr</sub>	Reverse Recovery Charge	_	2.6	_	uC	di/dt = 100A/µs

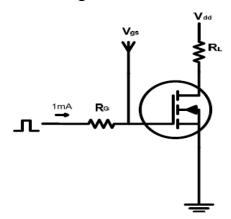


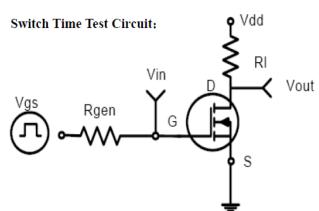
### **Test circuits and Waveforms**



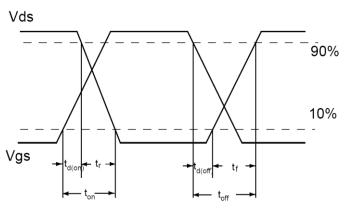


#### Gate charge test circuit:







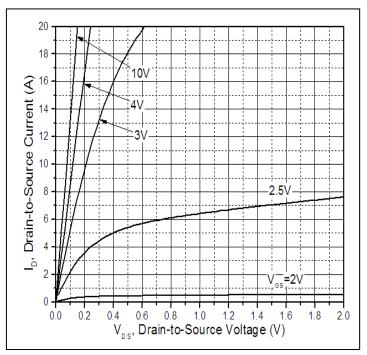


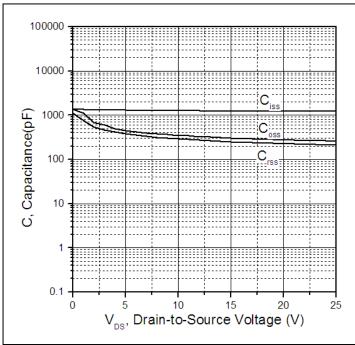
#### Notes:

- ①The maximum current rating is limited by bond-wires.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-ambient thermal resistance.
- 4The value of  $R_{\theta JA}$  is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- ⑤These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}=150$ °C.



## Typical electrical and thermal characteristics





**Figure 1.Typical Output Characteristics** 

Figure 2. Typical Capacitance Vs. Drain-to-Source Voltage

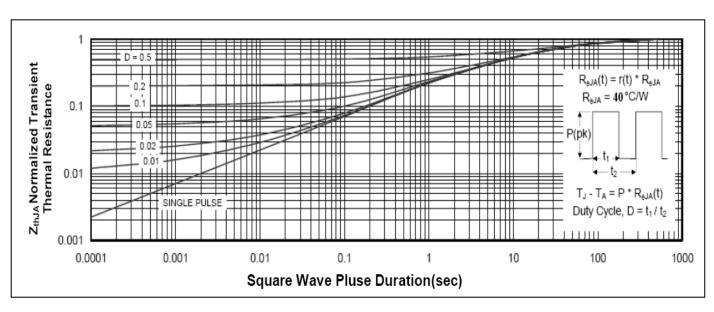
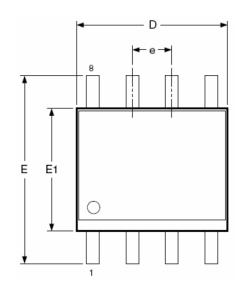


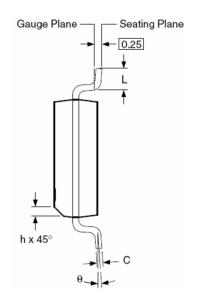
Figure 3. Maximum Effective Transient Thermal Impedance, Junction-to-Case

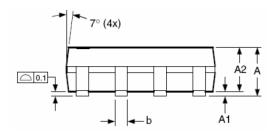


### **Mechanical Data:**

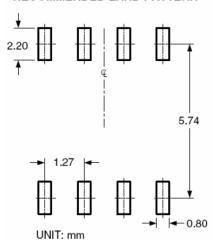
#### **SOP-8 PACKAGE OUTLINE DIMENSION**







#### RECOMMENDED LAND PATTERN



### Dimensions in millimeters

Symbols	Min.	Nom.	Max.		
Α	1.35	1.65	1.75		
A1	0.10	_	0.25		
A2	1.25	1.50	1.65		
b	0.31	_	0.51		
С	0.17	_	0.25		
D	4.80	4.90	5.00		
E1	3.80	3.90	4.00		
е	1.27 BSC				
E	5.80	6.00	6.20		
h	0.25	_	0.50		
L	0.40		1.27		
θ	0°	_	8°		

### Dimensions in inches

Symbols	Min.	Nom.	Max.
Α	0.053	0.065	0.069
A1	0.004	_	0.010
A2	0.049	0.059	0.065
b	0.012	_	0.020
С	0.007	_	0.010
D	0.189	0.193	0.197
E1	0.150	0.154	0.157
е	0	.050 BS	С
E	0.228	0.236	0.244
h	0.010	_	0.020
L	0.016		0.050
θ	0°	_	8°





## **Ordering and Marking Information**

Device Marking: SSF3610E

Package (Available)
SOP-8
Operating Temperature Range
C: -55 to 150 °C

## **Devices per Unit**

Package	Units/	Tapes/Inner	Units/Inner	Inner	Units/Carton
Type	Tape	Box	Box	<b>Boxes/Carton</b>	Box
	_				
				Box	

**Reliability Test Program** 

Test Item	Conditions	Duration	Sample Size
High	T <sub>j</sub> =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V <sub>DSS</sub> /V <sub>CES</sub> /VR	1000 hours	
Bias(HTRB)			
High	T <sub>j</sub> =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V <sub>GSS</sub>	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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